

## MLCC APPLICATION GUIDE



No.	Process	Condition							
1	Operating Condition (Storage)	1) The capacitor must be stored in an ambient temperature between 5 ~ $40^{\circ}$ C with a relative humidity of 20 ~ 70%. The products should be used within 12 months upon receipt.							
	(otorago)	2) The capacitors must be operated and stored in an environment free of dew condensation and these gases such as Hydrogen Sulphide, Hydrogen Sulfate, Chlorine and Ammonia and sulfur.							
		3) Avoid storing in direct sunlight and falling of dew.							
4) Do not use capacitors under high humidity and high and low atmospheric pressure w capacitors reliability.									
2	Circuit	2-1 Operating temperature							
-	design	Operating temperature should be followed strictly within this specification, especially be careful with maximum temperature.							
	! Caution	1) Do not use capacitor above the maximum allowable operating temperature.							
		<ul> <li>2) Surface temperature including self heating should be below maximum operating temperature. (Due to dielectric loss, capacitor will heat itself when AC is applied. Especially at high frequencies around its SRF, the heat might be so extreme that it may damage itself or the surrounding area. Please design the circuit so that the maximum temperature of the capacitor including the self heating to be below the maximum allowable operating temperature. Temperature rise shall be below 20°C)</li> <li>2-2 Operating voltage</li> <li>1) Operating voltage across the terminals should be below the rated voltage. When AC and DC are super imposed, the peak must be below the rated voltage. With AC or pulse overshooting, Vp-p must be below the rated voltage.</li> <li>AC or Pulse with overshooting, Vp-p must be below the rated voltage.</li> <li></li></ul>							
		Positional Measurement $V_{D-p}$ (1) $V_{D-p}$ (2) $V_{D-p}$ (3) $V_{D-p}$ (4) $V_{D-p}$ (5) $V_{D-p}$ (5)							
		<ol> <li>2) Even below the rated voltage, if repetitive high frequency AC or pulse is applied, the reliability of the capacitor may be reduced.</li> <li>3) Voltage derating will greatly reduce the failure rate. Since the failure rate follows the 3 power law of voltage, the failure rate used under Uw with UR rated product will be lowered as (Uw/UR)<sup>3</sup>.</li> </ol>							

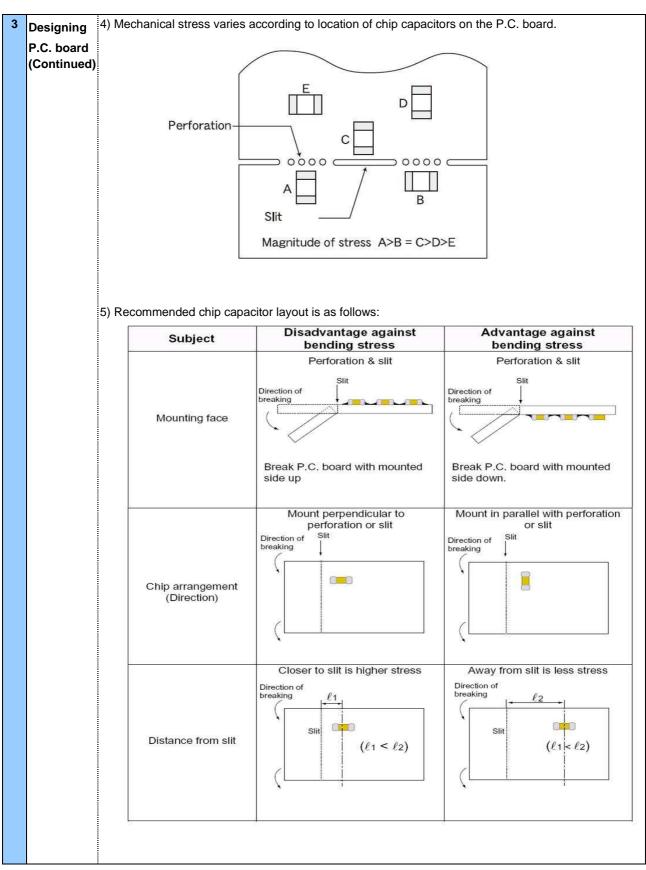
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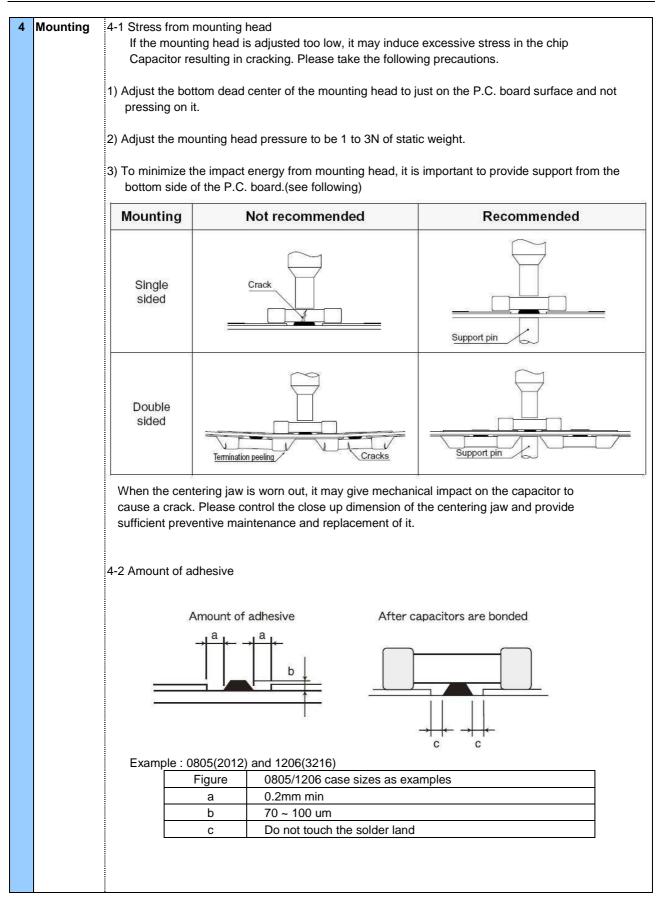
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3	Designing	The amount of solder at the terminations has a direct effect on the reliability of the capacitor.												
	P.C. board	<ol> <li>The greater the amount of solder, the higher the stress on the chip capacitor, and the more likely that it will break. When designing a P.C. board, determine the shape and size of the solder pads to have proper amount of solder on the terminations.</li> </ol>												
		each termir	e) Avoid using common solder pads for multiple terminations and provide individual solder pads for each terminations. See the following table for recommended pad dimensions											
See the following table for recommended pad dimensions.														
		C B Solder resist pattem												
		A F F												
Reflow Soldering														
			Footprint dimensions in mm         Processing         P								Placement			
		SIZE	Α	В	С	D	Е	F	G	remarks	Accuracy			
		01005	0.45	0.20	0.15	0.21	N/A	0.65	0.38		± 0.05			
		0201	0.65	0.23	0.21	0.30	N/A	0.90	0.60		± 0.05			
		0402	1.50	0.40	0.50	0.50	0.10	1.75	0.95		± 0.15			
		0508	2.50	0.50	1.00	2.00	0.15	2.90	2.40		± 0.20			
		0505	3.43	0.94	1.42	2.11	N/A	N/A	N/A		± 0.25			
		0603	2.30	0.70	0.80	0.80	0.20	2.55	1.40		± 0.25			
		0612	2.80	0.80	1.00	3.20	0.20	3.08	3.85		± 0.25			
		0805	2.80	1.00	0.90	1.30	0.40	3.05	1.85	Reflow or hot	± 0.25			
		1111	4.62	2.01	1.42	3.45	N/A	N/A	N/A	plate soldering	± 0.25			
		1206	4.00	2.20	0.90	1.60	1.60	4.25	2.25		± 0.25			
		1210	4.00	2.20	0.90	2.50	1.60	4.25	3.15		± 0.25			
		1808	5.40	3.30	1.05	2.30	2.70	5.80	2.90		± 0.25			
		1825	5.30	3.50	0.90	6.50	N/A	N/A	N/A		± 0.30			
		1812	5.30	3.50	0.90	3.80	3.00	5.55	4.05		± 0.25			
		2211	7.00	4.30	1.35	3.70	N/A	7.60	4.10		± 0.30			
		2220	7.00	4.30	1.35	5.00	N/A	7.60	5.50		± 0.30			
		2225	7.00	4.30	1.35	6.50	N/A	N/A	N/A		± 0.40			

No.	Process		Condition									
3	Designing	,	Wave Soldering									
	P.C. board (Continued)		Footprint dimensions in						nm		Proposed	
	(,	SIZE		<b>A</b>				EF		G	number & Dimensions	Placement
			SIZE	A	Ь	C	U	<b>-</b>	г	G	of dummy tracks	Accuracy
			0603	2.40	1.00	0.70	0.80	0.20	3.10	1.90	1x (0.20x0.80)	± 0.10
			0805	3.20	1.40	0.90	1.30	0.36	4.10	2.50	1x (0.30x1.30)	± 0.15
			1206	4.80	2.30	1.25	1.70	1.25	5.90	3.20	3x (0.25x1.70)	± 0.25
			1210	5.30	2.30	1.50	2.60	1.25	6.30	4.20	3x (0.25x2.60)	± 0.25
		Footprint design for C Array :										
			Ту	ре		0603*4		04	02*4		1	
				4	2.85	2.85 +0.10/-0.05		1.80 ± 0.10				
			I	В	0.45 ± 0.05			0.25 ± 0.05				
			[	D	0.80 ± 0.10			0.65 ± 0.05			•	
			I	P	0.80			0.50		A		
		F		F	3.10 ± 0.30				1.85 ± 0.25		<b>N</b>	7
		3) L	ayout recor	mmenda	ition							
			Example	Us		nmon s and	older		dering v chassis		Use of common land with other	
		Must be avoided		PC	Lead wire Chip Solder PCB Adhesive Solder pad			Chassis Excessive solder		Solder pad Excessive solder Missing solder		
	Re		Recommend	ded			wire	Solder resist $\ell_2 > \ell_1$			Solder re	sist
		633										



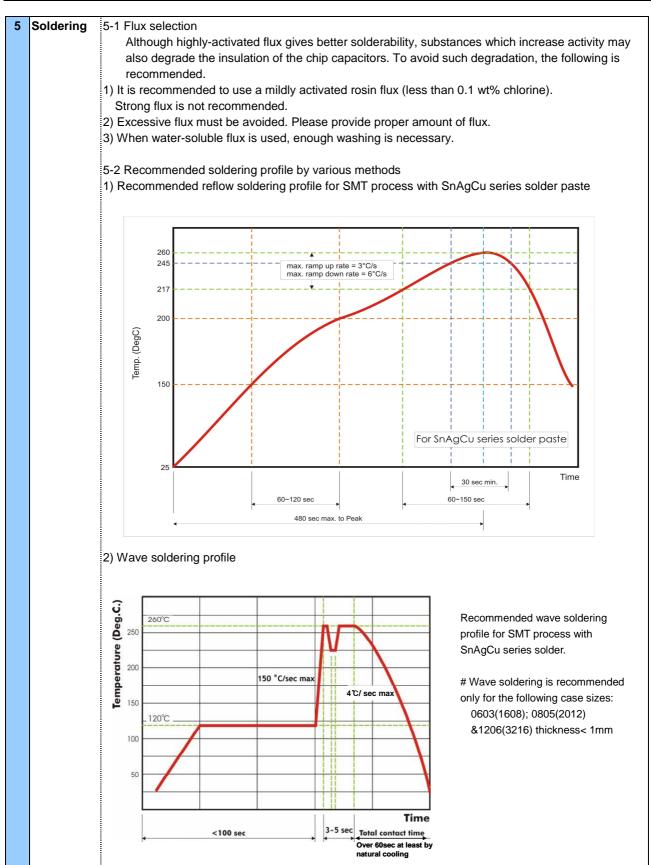




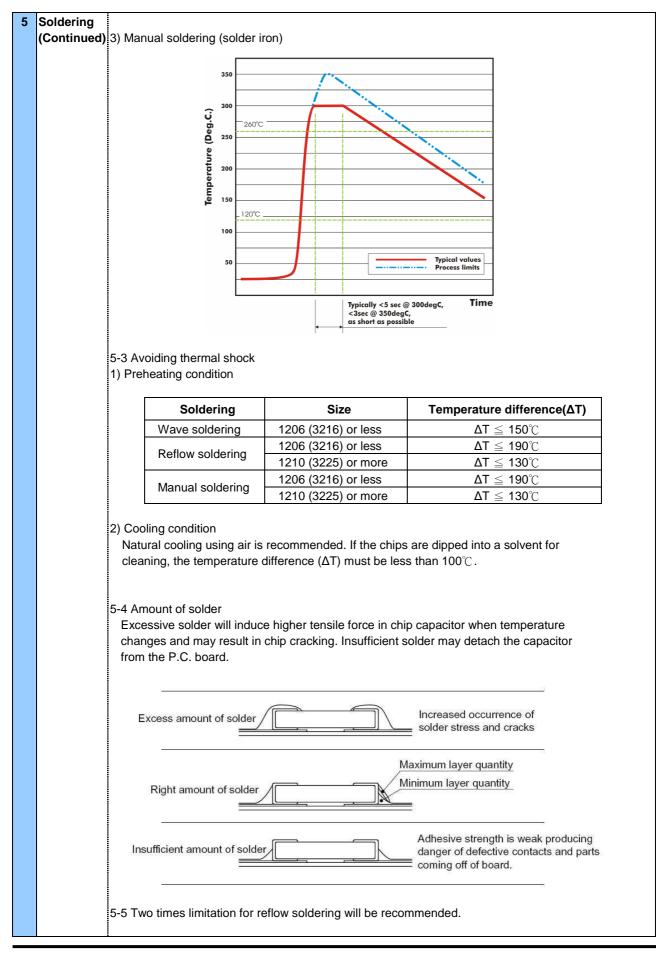


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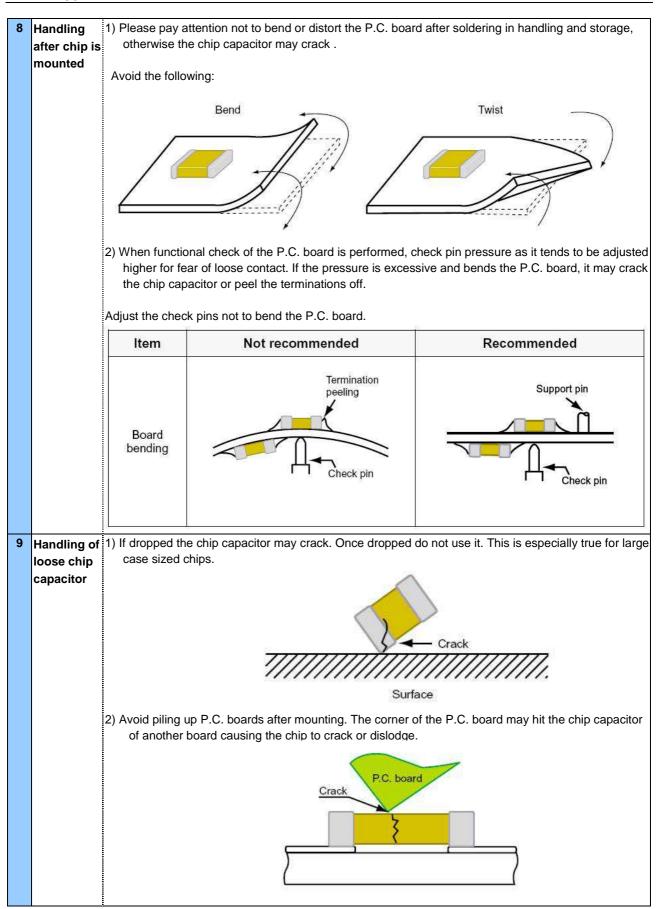






		-6 Solder repair by solder iron ) Selection of the soldering iron tip Tip temperature of solder iron varies by its type, P.C. board material and solder pad size. Higher tip temperature may be faster, but the heat shock may crack the chip capacitor. (Following conditions are recommended.) Size Temp. (°C) Preheating Temperature difference(ΔT) Atmosphere									
		1206 (3216) or less350°C Max>150°C $\Delta T \leq 190°C$ Room air									
	1210 (3225) or more280°C Max>150°C $\Delta T \leq 130°C$ Room at										
		<ul> <li>2) Direct contact of the soldering iron with ceramic dielectric of chip capacitor may cause cracking. Do not make contact directly with the ceramic dielectric.</li> <li>Hand soldering method</li> </ul>									
6	Cleaning	<ul> <li>Cleaning         <ol> <li>If an unsuitable cleaning fluid is used, flux residue or some foreign article may stick to chip capacity surface causing deteriorated performance, especially insulation resistance.</li> <li>If the cleaning condition is not suitable, it may damage the chip capacitor.</li> </ol> </li> </ul>									
		<ul> <li>2-1) Insufficient washing <ul> <li>(1) Lead wire and terminal electrodes may corrode due to Halogen in the flux.</li> <li>(2) Halogen in the flux may adhere on the surface of capacitor, and lower the insulation resistance.</li> <li>(3) Water soluble flux has higher tendency to have the above mentioned problems (1) and (2).</li> </ul> </li> <li>2-2) Excessive washing <ul> <li>When ultrasonic cleaning is used, excessively high ultrasonic energy output can affect the connection between the ceramic chip capacitor's body and the terminal electrode. To avoid this, use the following recommended condition. <ul> <li>Power : 20W/I max.</li> <li>Frequency : 40kHz max.</li> <li>Washing time : 5 minutes max.</li> </ul> </li> </ul></li></ul>									
		<ul> <li>2-3) If the cleaning fluid is contaminated, the density of Halogen increases, and it may bring the same result as insufficient cleaning.</li> <li>3) Selection of cleaning fluid In general, washing is not necessary if rosin-based flux is used. When using active flux, suitable cleaning fluids are water, isopropyl or a solvent that has the capability to remove the flux.</li></ul>									
		<ol> <li>Precautions</li> <li>After the reflow process, wait at least 5 minutes before proceeding with the cleaning procedure.</li> </ol>									
7	Coating and	1) When the P.C. board is			-						
	molding of the P.C. board	<ul><li>2) Please verify that there may damage the chip</li></ul>	is no harmful dec			during curing which					
		3) Please verify the curing	temperature.								

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華新科技股份有限公司

Walsin Technology Corporation